

40V N-Channel Enhancement Mode Power MOSFET

Description

WMQ50N04T1 uses advanced power trench technology that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

Features

- $V_{DS} = 40V$, $I_D = 50A$
- $R_{DS(on)} < 7.2m\Omega$ @ $V_{GS} = 10V$
 $R_{DS(on)} < 8.5m\Omega$ @ $V_{GS} = 4.5V$
- Green Device Available
- Low Gate Charge
- Low $R_{DS(ON)}$
- 100% EAS Guaranteed
- Lead Free Product is Acquired

Applications

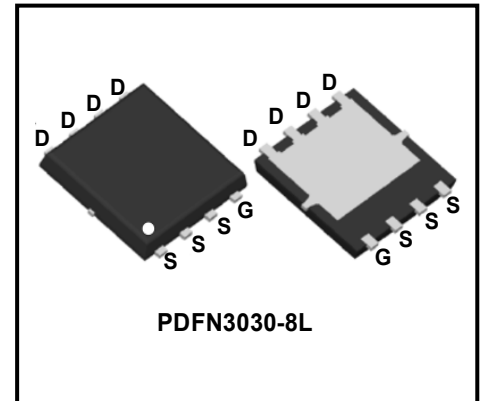
- Power Management Switches
- DC/DC Converter

Absolute Maximum Ratings ($T_A = 25^\circ C$, unless otherwise noted)

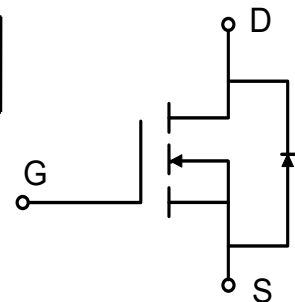
Parameter		Symbol	Value	Unit
Drain-Source Voltage		V_{DS}	40	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ C$	I_D	50	A
	$T_C = 100^\circ C$		32	
Pulsed Drain Current ¹		I_{DM}	200	A
Single Pulse Avalanche Energy ²		EAS	45	mJ
Total Power Dissipation	$T_C = 25^\circ C$	P_D	22.7	W
Operating Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	$^\circ C$

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance from Junction-to-Ambient ³	$R_{\theta JA}$	63	$^\circ C/W$
Thermal Resistance from Junction-to-Case	$R_{\theta JC}$	5.5	$^\circ C/W$



RoHS
compliant



Electrical Characteristics ($T_J = 25^\circ\text{C}$, unless otherwise noted)

Parameter		Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics							
Drain-Source Breakdown Voltage		$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	40	-	-	V
Gate-Body Leakage Current		I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	± 100	nA
Zero Gate Voltage Drain Current	$T_J=25^{\circ}C$	I_{DSS}	$V_{DS} = 40V, V_{GS} = 0V$	-	-	1	μA
	$T_J=100^{\circ}C$			-	-	100	
Gate-Threshold Voltage		$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.0	1.6	2.5	V
Drain-Source On-Resistance ⁴		$R_{DS(on)}$	$V_{GS} = 10V, I_D = 30A$	-	5.5	7.2	m Ω
			$V_{GS} = 4.5V, I_D = 20A$	-	6.5	8.5	
Forward Transconductance ⁴		g_{fs}	$V_{DS} = 10V, I_D = 30A$	-	28	-	S
Dynamic Characteristics ⁵							
Input Capacitance		C_{iss}	$V_{DS} = 20V, V_{GS} = 0V, f = 1MHz$	-	2365	-	pF
Output Capacitance		C_{oss}		-	185	-	
Reverse Transfer Capacitance		C_{rss}		-	143	-	
Gate Resistance		R_g	$f = 1MHz$	-	2.3	-	Ω
Switching Characteristics ⁵							
Total Gate Charge		Q_g	$V_{GS} = 10V, V_{DS} = 20V, I_D = 30A$	-	36	-	nC
Gate-Source Charge		Q_{gs}		-	6.2	-	
Gate-Drain Charge		Q_{gd}		-	7.3	-	
Turn-On Delay Time		$t_{d(on)}$	$V_{GS} = 10V, V_{DD} = 20V, R_G = 3\Omega, I_D = 30A$	-	9.2	-	ns
Rise Time		t_r		-	12	-	
Turn-Off Delay Time		$t_{d(off)}$		-	45	-	
Fall Time		t_f		-	6.7	-	
Body Diode Reverse Recovery Time		t_{rr}	$I_F = 30A, dI/dt = 100A/\mu s$	-	34	-	ns
Body Diode Reverse Recovery Charge		Q_{rr}		-	3.8	-	nC
Drain-Source Body Diode Characteristics							
Diode Forward Voltage ⁴		V_{SD}	$I_S = 1A, V_{GS} = 0V$	-	-	1.2	V
Continuous Source Current	$T_C=25^{\circ}C$	I_S	-	-	-	50	A

Note :

1. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)} = 150^\circ\text{C}$.
2. The EAS data shows Max. rating . The test condition is $V_{DD} = 25V, V_{GS} = 10V, L = 0.1\text{mH}, I_{AS} = 30A$
3. The data tested by surface mounted on a 1 inch2 FR-4 board with 20Z copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.
5. This value is guaranteed by design hence it is not included in the production test.

Typical Characteristics

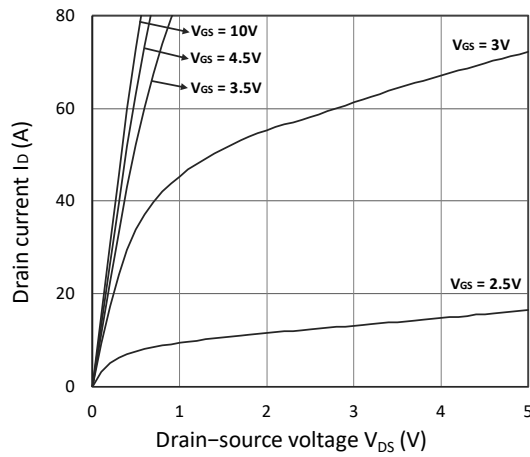


Figure 1. Output Characteristics

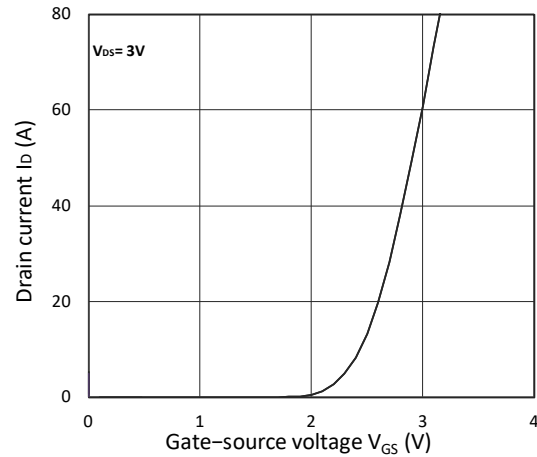


Figure 2. Transfer Characteristics

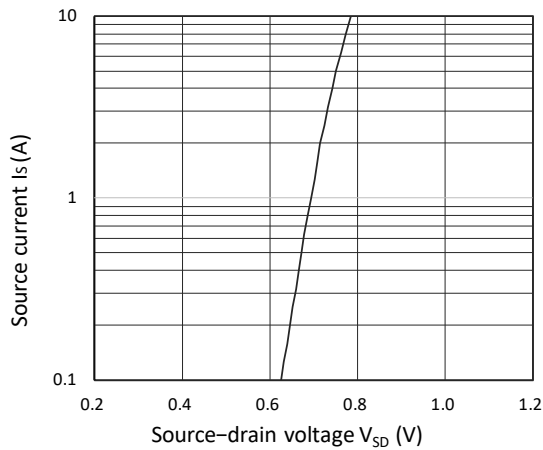
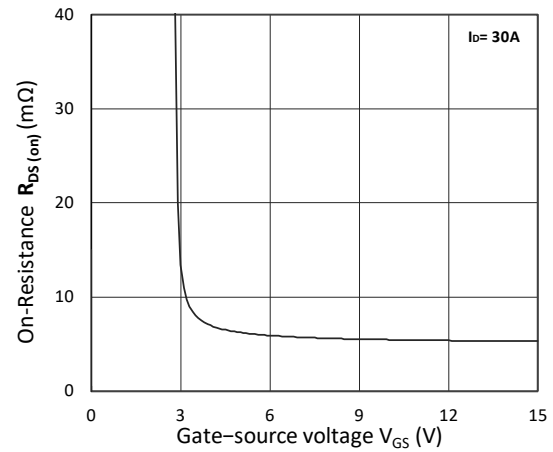
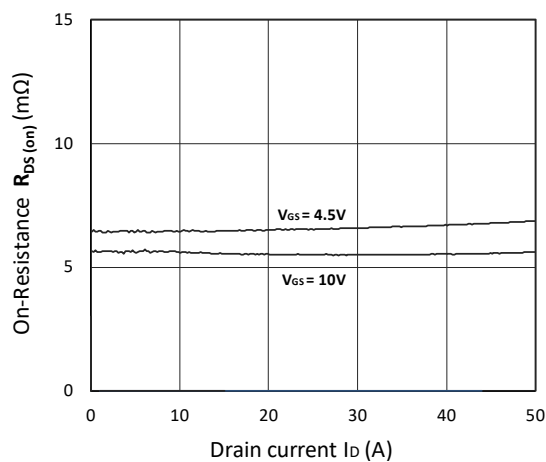
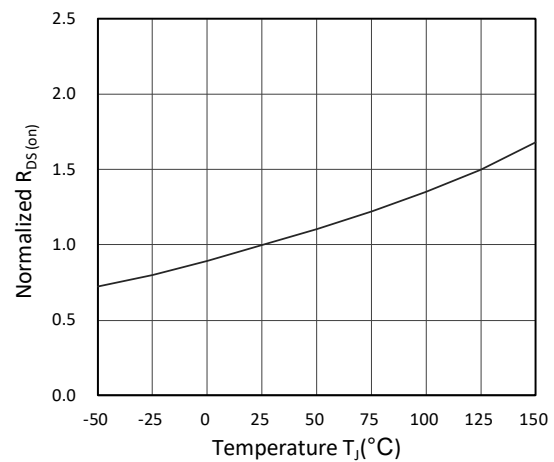


Figure 3. Forward Characteristics of Reverse

Figure 4. $R_{DS(on)}$ vs. V_{GS} Figure 5. $R_{DS(on)}$ vs. I_D Figure 6. Normalized $R_{DS(on)}$ vs. Temperature

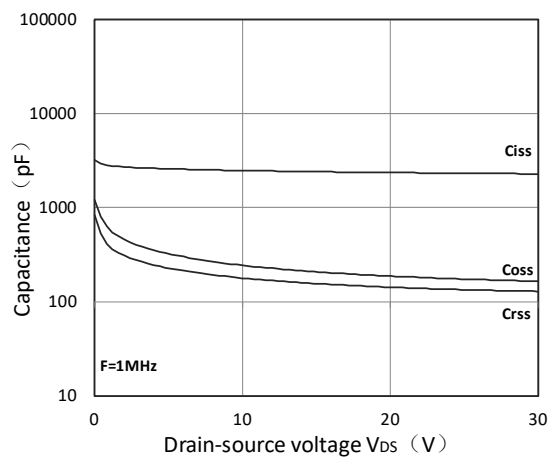


Figure 7. Capacitance Characteristics

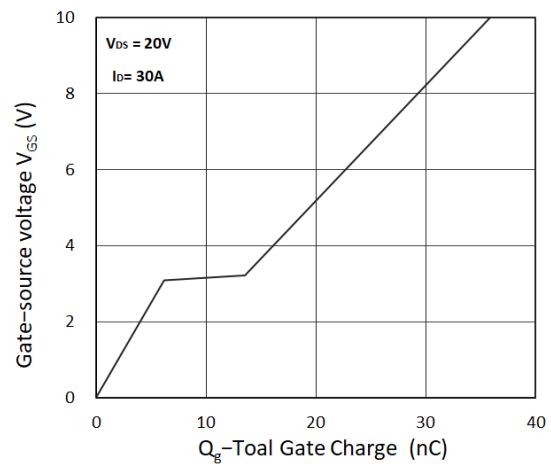


Figure 8. Gate Charge Characteristics

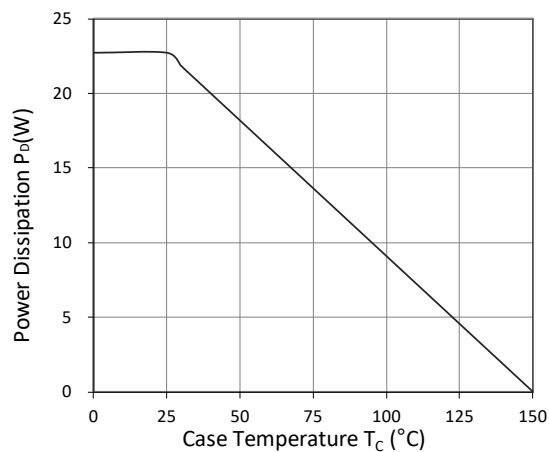


Figure 9. Power Dissipation

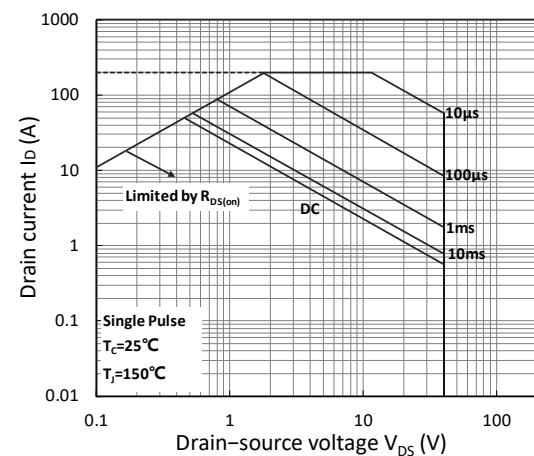


Figure 10. Safe Operating Area

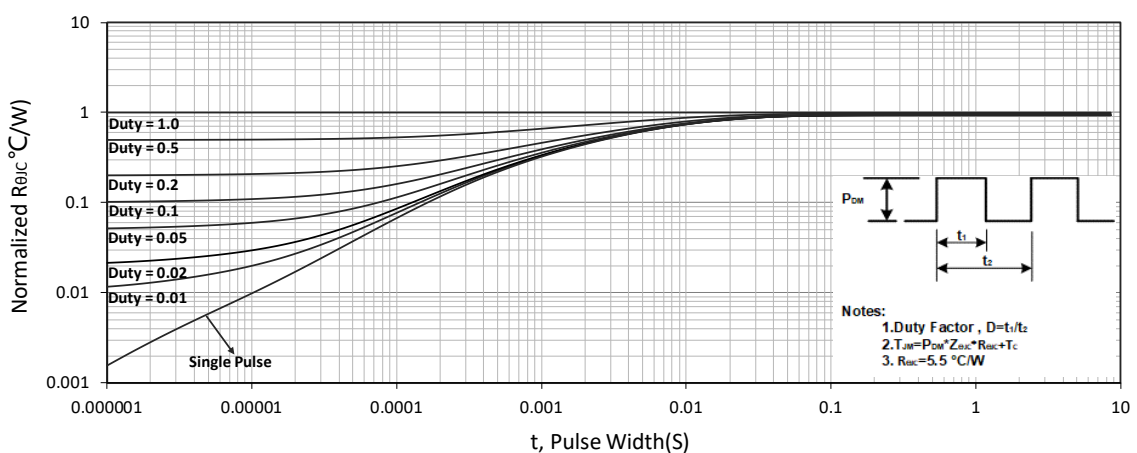


Figure 11. Normalized Maximum Transient Thermal Impedance

Test Circuit

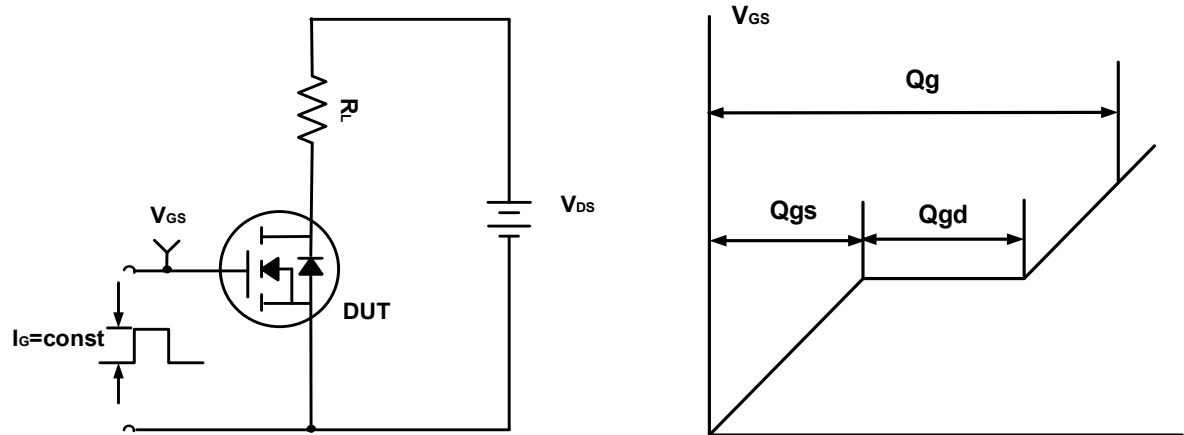


Figure A. Gate Charge Test Circuit & Waveforms

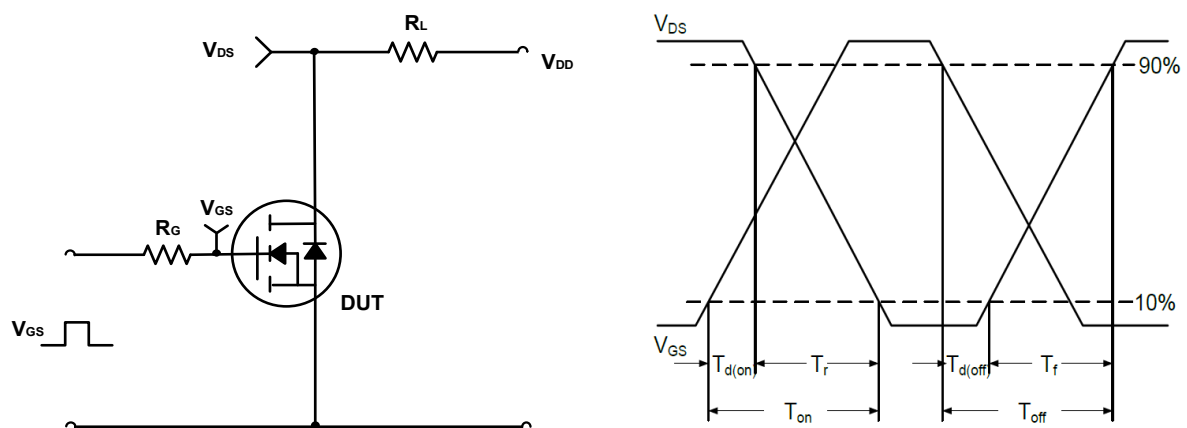


Figure B. Switching Test Circuit & Waveforms

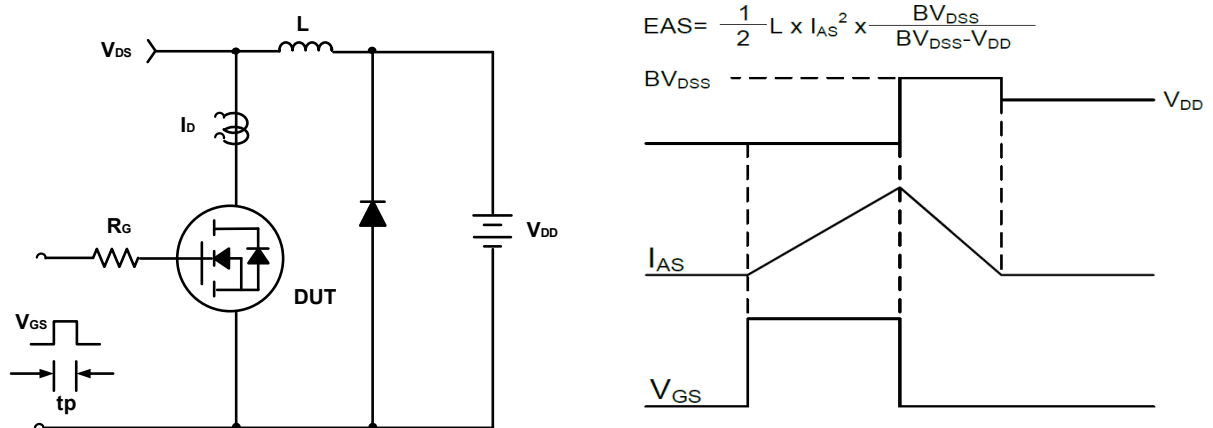
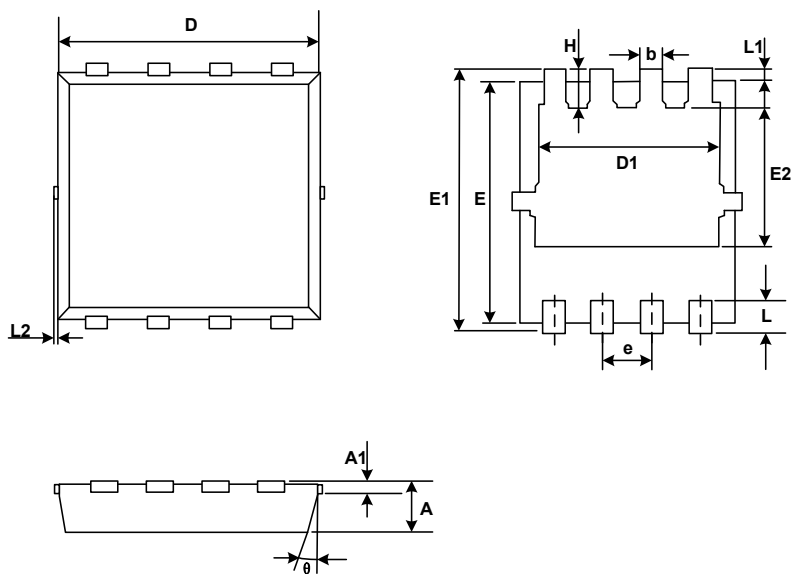


Figure C. Unclamped Inductive Switching Circuit & Waveforms

Mechanical Dimensions for PDFN3030-8L



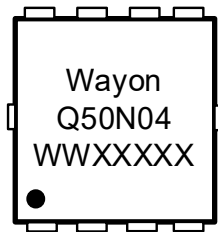
COMMON DIMENSIONS

SYMBOL	MM	
	MIN	MAX
A	0.65	0.90
A1	0.10	0.25
D	2.90	3.25
D1	2.25	2.69
E	2.90	3.20
E1	3.00	3.60
E2	1.35	2.20
b	0.20	0.40
e	0.65BSC	
L	0.15	0.50
L1	0.13BSC	
L2	0.00	0.20
H	0.15	0.65
θ	0°	14°

Ordering Information

Part	Package	Marking	Packing method
WMQ50N04T1	PDFN3030-8L	Q50N04	Tape and Reel

Marking Information



Q50N04 = Device code
WWXXXXX= Date code

Contact Information

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